

Supplementary Information

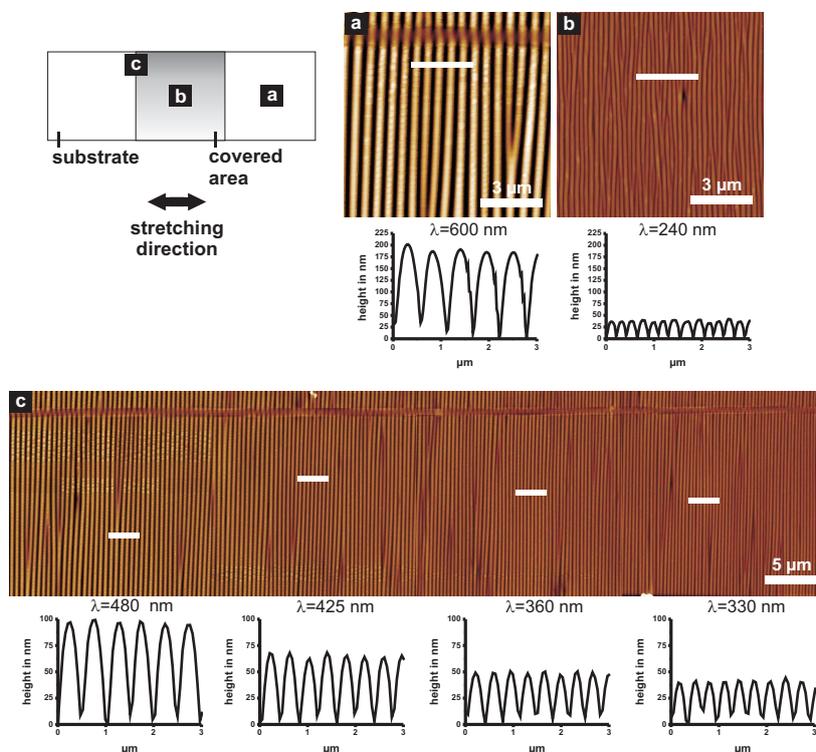


Figure 6: Sketch of gradient sample (150 s plasma treatment) with letters indicating the points of measurement and corresponding AFM height images (a-c). The grey area represents the area covered by the silicon wafer. A cross section is depicted underneath each AFM image. Height scale: a-c:175 nm.

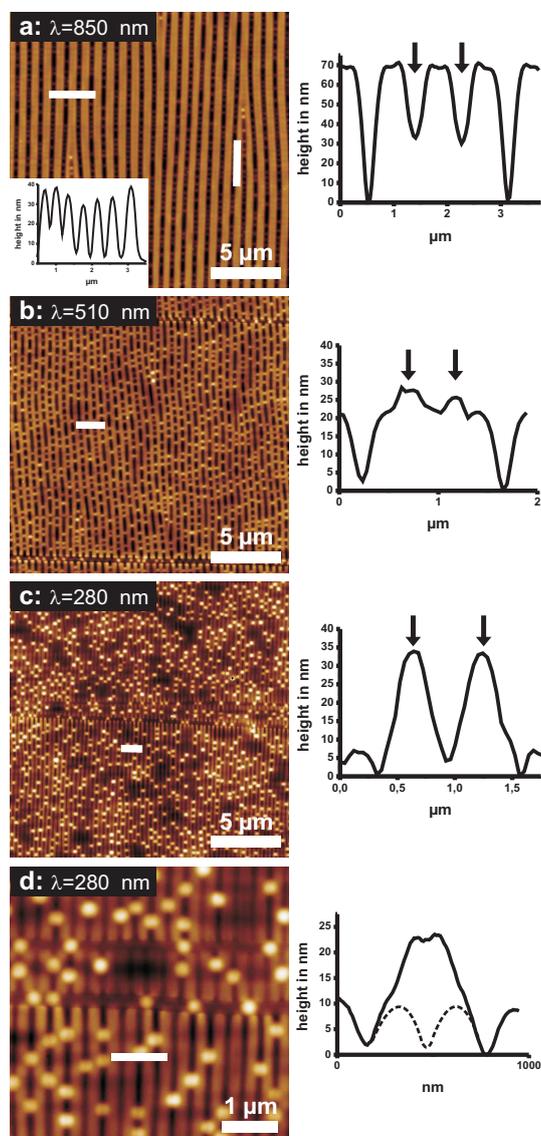


Figure 7: AFM height images of VCL/NiPAAm (83:17) microgels assembled on wrinkle gradient at λ of 850 (a), 510 (b) and 280 nm (c) with cross sections. Inset in (a) shows cross section along wrinkle direction. (d): Higher magnification of microgel at $\lambda=280$ nm with cross section showing indentation/flexibility of microgel. Arrows mark the position of a microgel particle in the cross sections. Height scale: a=120 nm, b-d=60 nm.

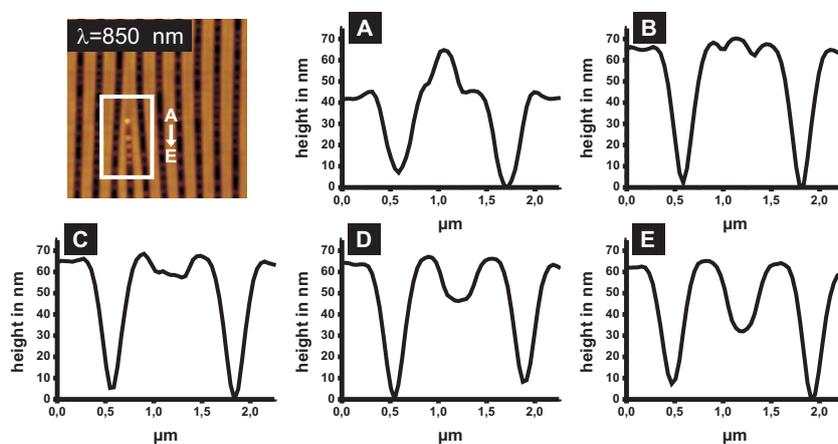


Figure 8: AFM height image of VCL/NiPAAm (83:17) microgels assembled in a wrinkle defect yielding a gradient in wavelength. Cross sections show immersion of five particles (A-E) into the structure. Height scale: 120 nm.